Search Notes



SEARCHED

Date

1/22/2007

1/24/2007

7/2/2007

7/2/2007

7/2/2007

Examiner

JKT

JKT

JKT

JKT

JKT

Subclass

96,97

112

113, 114

115

. 330

Class

429

320

320

320

713

Application/Control No.	Applicant(s)/Patent under Reexamination
40/044 000	WILL EE THOMAS.

2116

10/611,638 Examiner

James K. Trujillo

WULFF, THOMAS Art Unit

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EAST (USPAT, US JPO, DERWENT, I attached; NPL: IEE Search/DP
Updated text searc
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
713	330	7/2/2007	JKT		
320	112,113	7/2/2007	JKT		
320	114, 115	7/2/2007	JKT		
See attached		7/2/2007	JKT		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	9/1/2006	JKT			
Updated text search, see attached	1/24/2007	JKT			
Updated text search, see attached	7/2/2007	JKT			